

Supplementary Information

Dielectric investigation on high-k Yttrium Copper Titanate thin films

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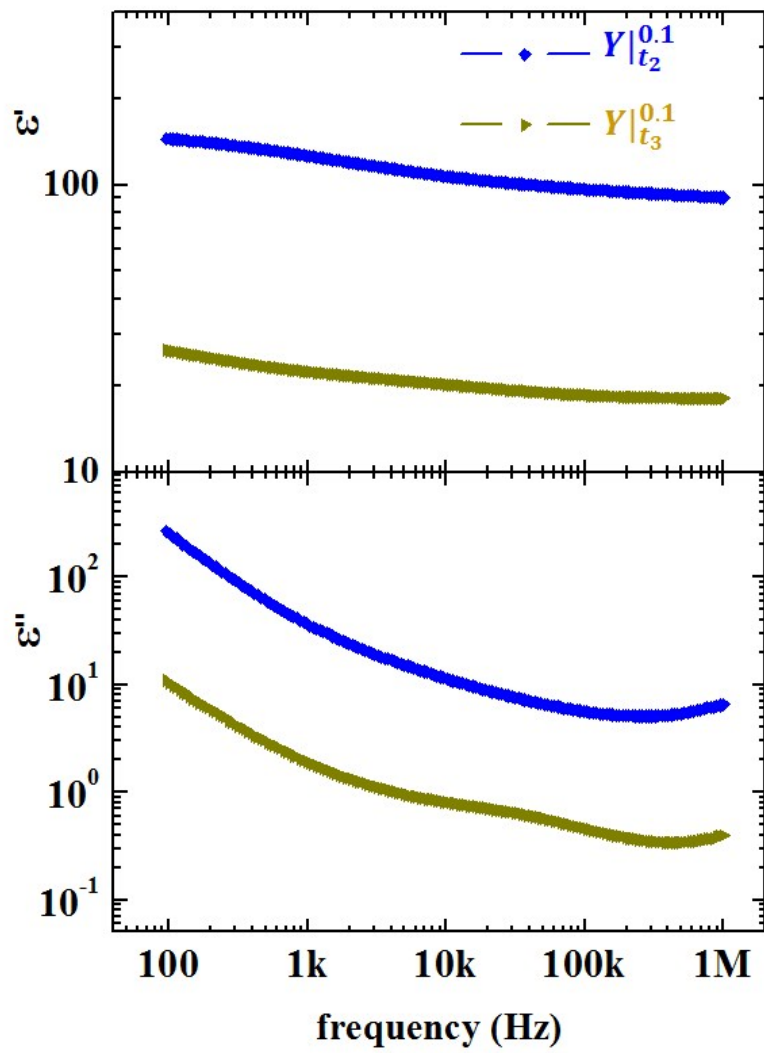


Fig. S1 Frequency dependences of real (ϵ') and imaginary part (ϵ'') of the complex permittivity in the frequency range 100Hz-1MHz for two YCTO films deposited at 0.1 Pa oxygen pressure with thickness $t_2=150\text{nm}$ and $t_3=50\text{nm}$.

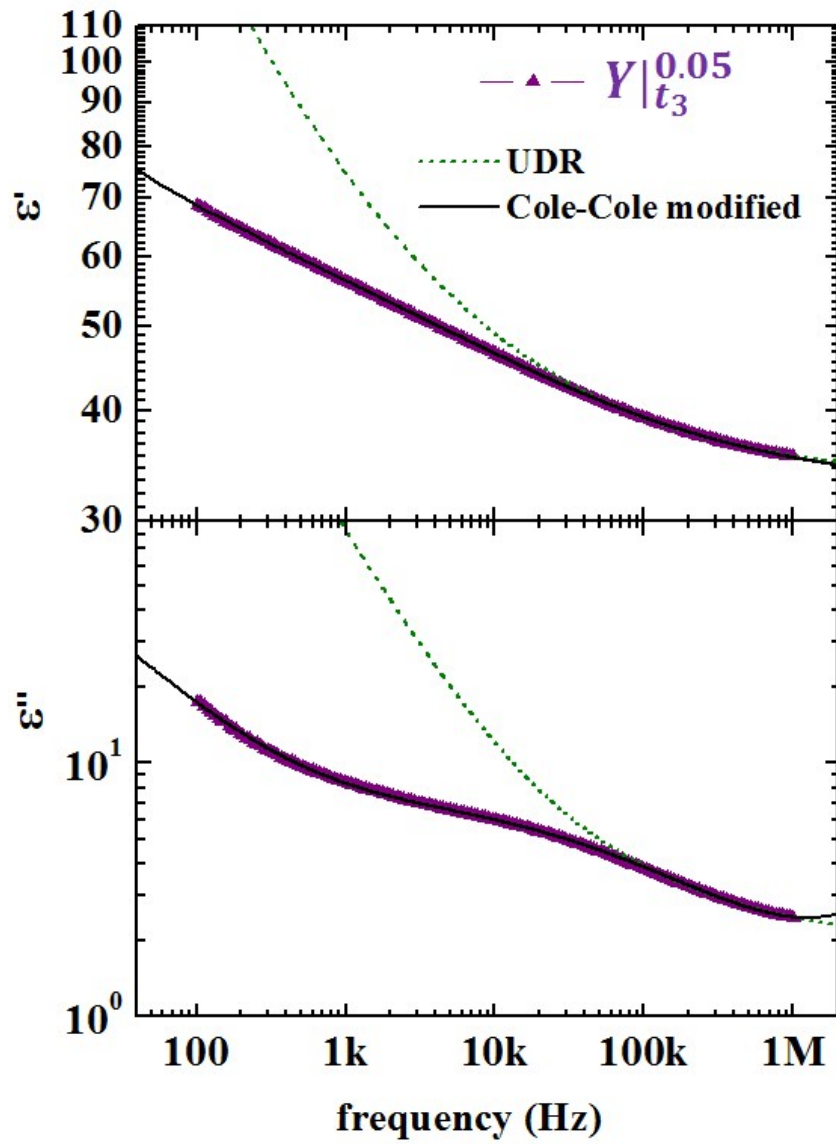


Fig. S2. $Y|_{t_3}^{0.05}$ film modeled by using the UDR and modified Cole-Cole models. The UDR model is able to describe only the high frequency behaviour of the complex permittivity, while the modified Cole-Cole model fits the data over the whole frequency range.